

Schmidt, N.B., & Joiner, T.E. (2004). Global maladaptive schemas, negative life events, and psychological distress. *Journal of Psychopathology and Behavioral Assessment*, 26, 65-72.

The relationship between maladaptive self-schemas, negative life events, and psychological distress was assessed. The model tested was based on Young's (J. Young, 1990) diathesis–stress conceptualization of maladaptive schemas, which are believed to represent the cognitive diathesis underlying Axis II personality pathology. Young's model predicts that schemas are chronically activated in individuals with maladaptive schemas. Therefore, the experience of salient negative life events is less likely to exacerbate the level of distress experienced by those having maladaptive schemas. A nonclinical sample (N = 93) was assessed using the Schema Questionnaire (SQ), a measure of maladaptive self-schemas, a measure of negative life events, and several measures of psychological distress. Support was found for this prediction indicated by a Schema × Negative Life Events interaction in which the distress level of High SQ participants was less affected by negative life events compared to Low SQ participants.